

Electronic Supplementary Information for

## **Controlled Integration of Oligo- and Polythiophenes at the Molecular Scale**

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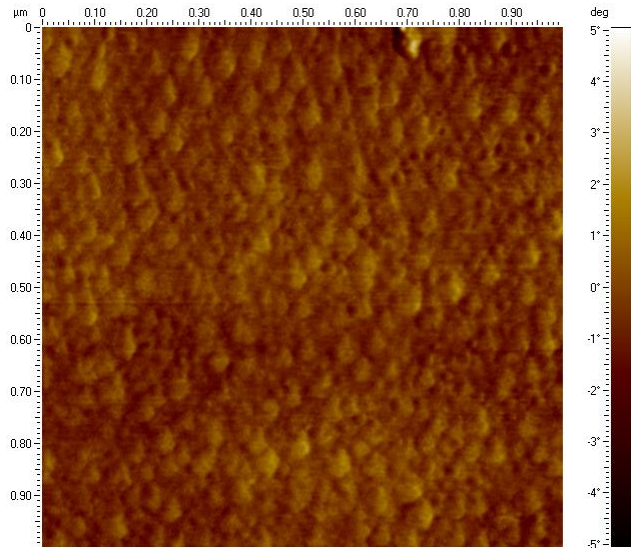
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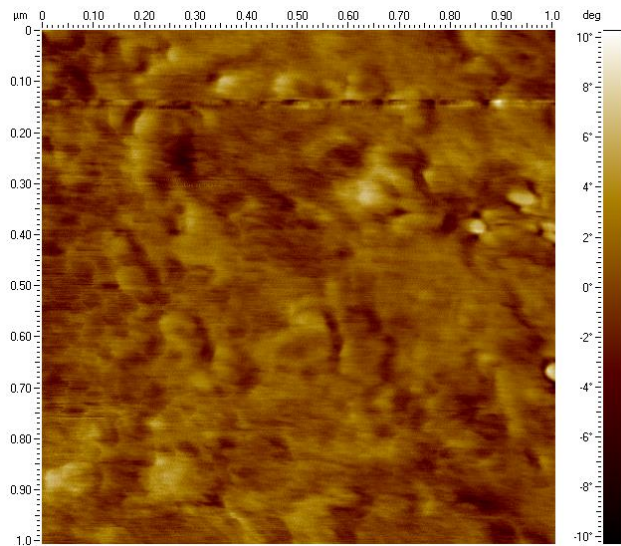
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S1. Atomic force micrographs: phase images of (a) 100% BTTT-3, (b) 87% BTTT-3 / 13% PBTTT, (c) 50% BTTT-3 / 50% PBTTT, (d) 13% BTTT-3 / 87% PBTTT, and (e) 100% PBTTT thin films. Scale bar is 200 nm. Vertical scale is in Å.

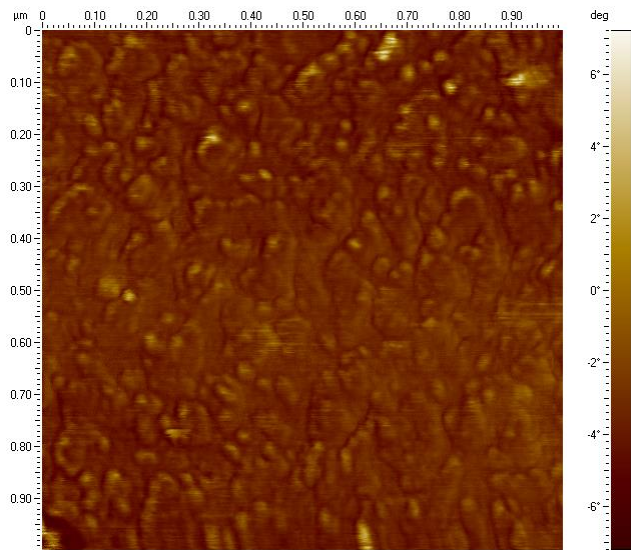
(a)



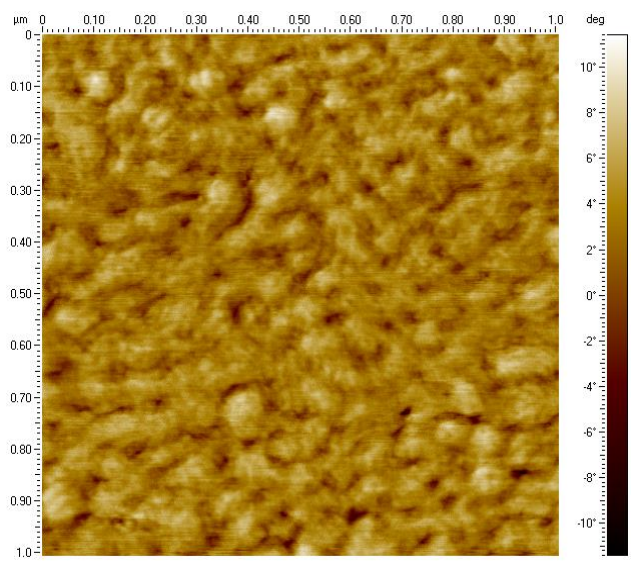
(b)



(c)



(d)



(e)

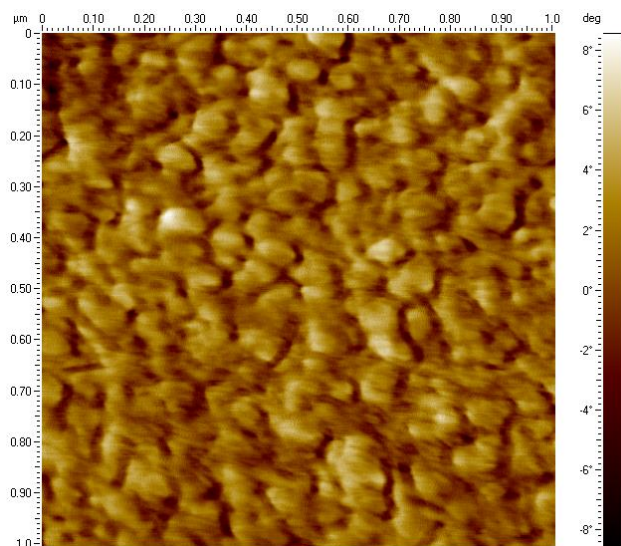


Table S1. RMS Roughness of films

Film	Roughness (Rq) (Å)
<b>BTTT-3</b>	4.8
<b>1:5</b>	9.3
<b>1:1</b>	9.4
<b>5:1</b>	13.0
<b>PBTTT</b>	10.9

Figure S2. GPC traces of PBTTT and BTTT-3

